

Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	ISM 2.4 GHz Band	Bluetooth, 10032-CAA	2402.000, 0	7.77	1.77	38.5

Hardware Setup

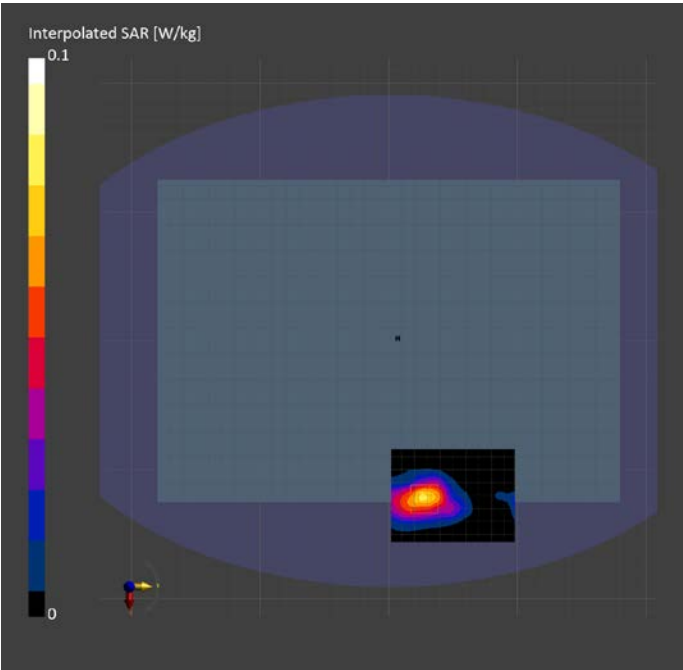
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h2450-260312,2026-03-12	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	72.0 x 96.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-12	2026-03-12
psSAR1g [W/kg]	0.061	0.057
psSAR10g [W/kg]	0.031	0.028
Power Drift [dB]		0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		71.5
Dist 3dB Peak [mm]		8.0



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Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	ISM 2.4 GHz Band	Bluetooth, 10670-AAA	2402.000, 0	7.77	1.77	38.5

Hardware Setup

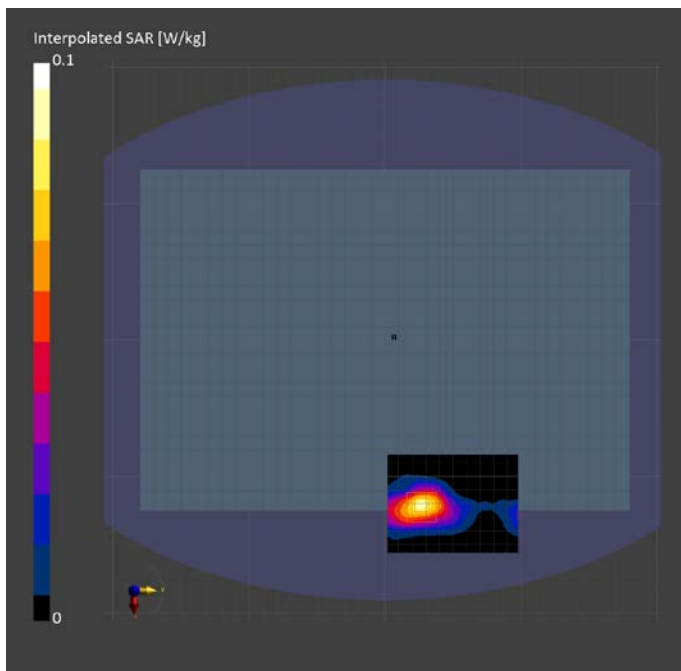
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h2450-260312 , 2026-03-12	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
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Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-12	2026-03-12
psSAR1g [W/kg]	0.068	0.071
psSAR10g [W/kg]	0.034	0.035
Power Drift [dB]		0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		79.7
Dist 3dB Peak [mm]		9.9



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Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	ISM 2.4 GHz Band	Bluetooth, 10032-CAA	2402.000, 0	7.77	1.77	38.5

Hardware Setup

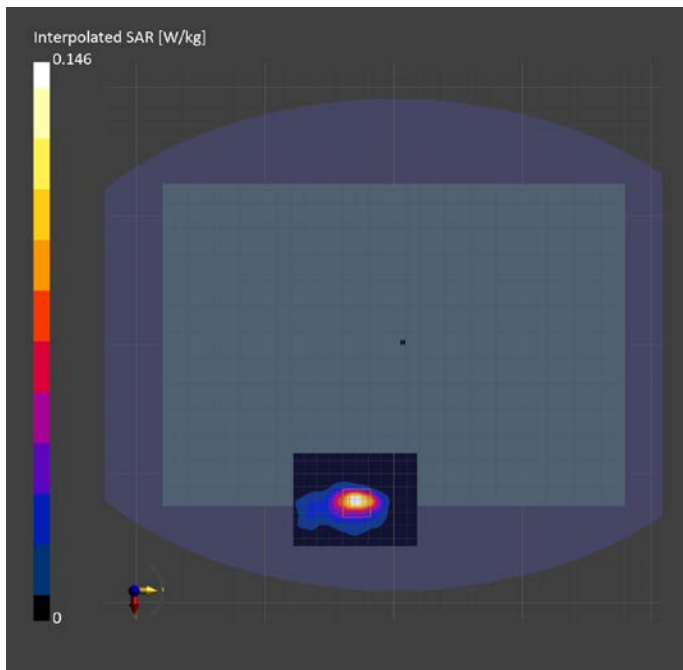
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h2450-260312, 2026-03-12	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	72.0 x 96.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-12	2026-03-12
psSAR1g [W/kg]	0.104	0.099
psSAR10g [W/kg]	0.044	0.045
Power Drift [dB]		-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		78.7
Dist 3dB Peak [mm]		7.0



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Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	ISM 2.4 GHz Band	Bluetooth, 10670-AAA	2402.000, 0	7.77	1.77	38.5

Hardware Setup

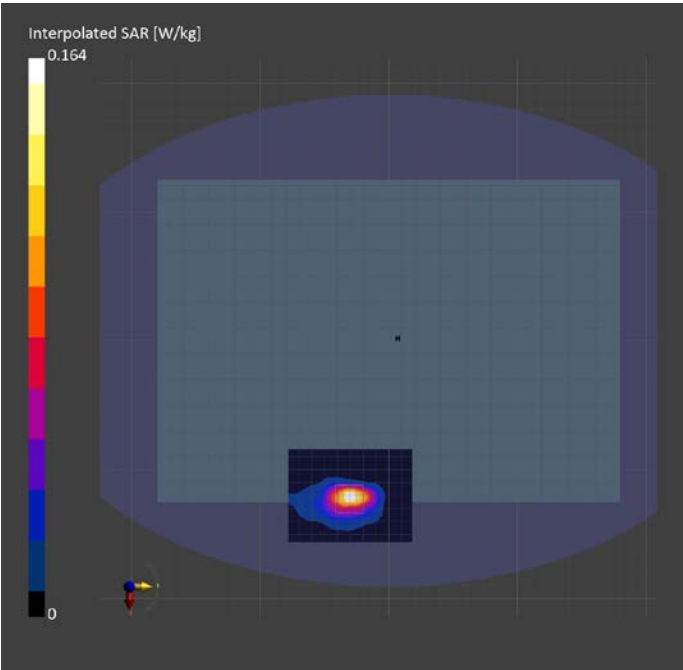
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h2450-260312,2026-03-12	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	72.0 x 96.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-12	2026-03-12
psSAR1g [W/kg]	0.118	0.111
psSAR10g [W/kg]	0.051	0.052
Power Drift [dB]		0.16
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		83.1
Dist 3dB Peak [mm]		8.0



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Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	WLAN, 2.4GHz	WLAN, 10616-AAD	2457.000, 10	7.77	1.81	38.2

Hardware Setup

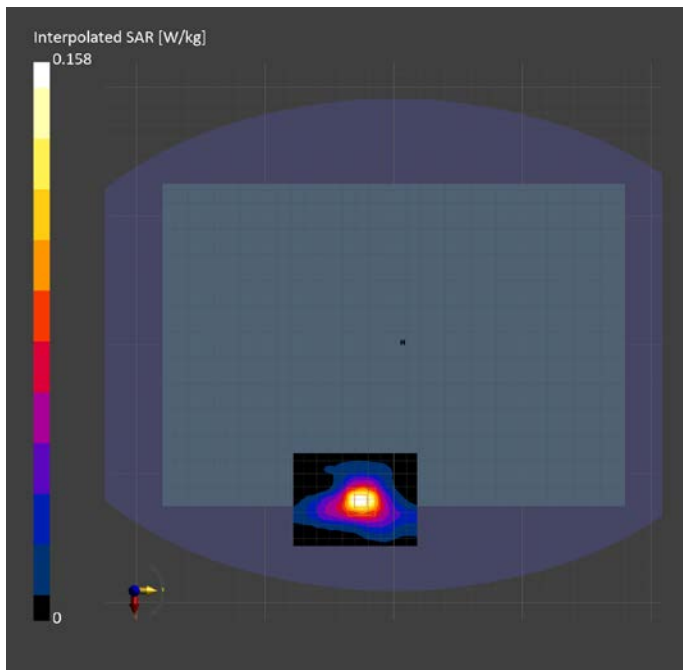
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h2450-260309, 2026-03-09	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	72.0 x 96.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-09	2026-03-09
psSAR1g [W/kg]	0.124	0.136
psSAR10g [W/kg]	0.060	0.065
Power Drift [dB]		-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		82.4
Dist 3dB Peak [mm]		10.0



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Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	WLAN, 2.4GHz	WLAN, 10616-AAD	2457.000, 10	7.77	1.81	38.2

Hardware Setup

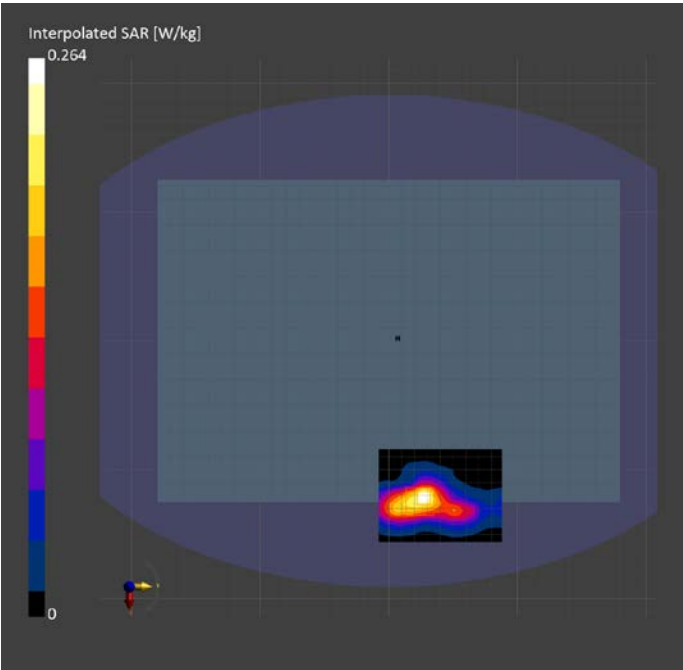
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h2450-260309,2026-03-09	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	72.0 x 96.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-09	2026-03-09
psSAR1g [W/kg]	0.199	0.207
psSAR10g [W/kg]	0.099	0.105
Power Drift [dB]		0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		83.2
Dist 3dB Peak [mm]		10.3



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Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	WLAN 2.4GHz	WLAN, 10616-AAD	2437.000, 6	7.77	1.80	38.2

Hardware Setup

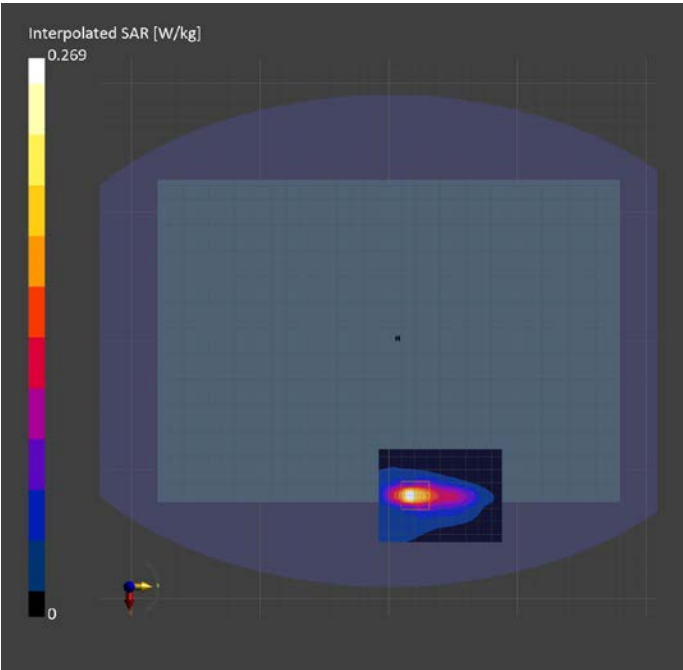
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h2450-260309,2026-03-09	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	72.0 x 96.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-09	2026-03-09
psSAR1g [W/kg]	0.185	0.186
psSAR10g [W/kg]	0.077	0.078
Power Drift [dB]		0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		79.8
Dist 3dB Peak [mm]		6.4



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Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	WLAN 2.4GHz	WLAN, 10616-AAD	2437.000, 6	7.77	1.80	38.2

Hardware Setup

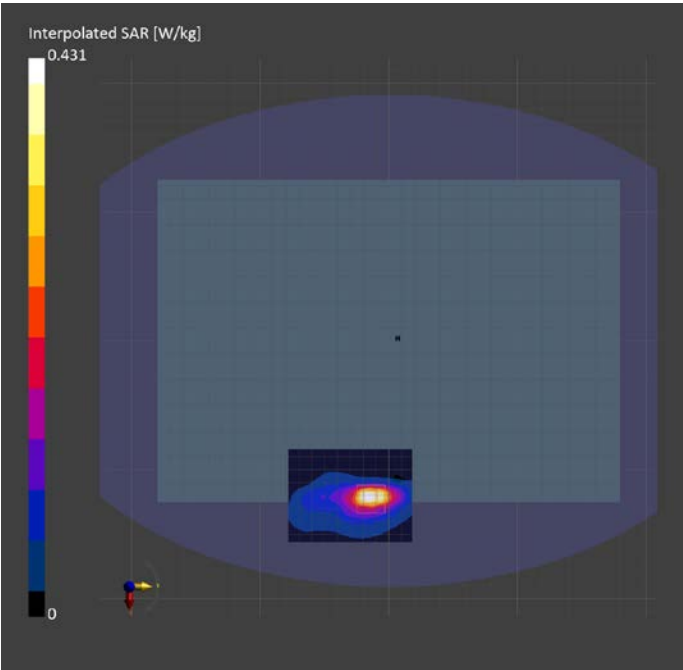
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h2450-260309,2026-03-09	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	72.0 x 96.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-09	2026-03-09
psSAR1g [W/kg]	0.322	0.341
psSAR10g [W/kg]	0.144	0.160
Power Drift [dB]		0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		85.0
Dist 3dB Peak [mm]		7.0



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Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	WLAN 5GHz	WLAN, 10554-AAE	5250.000, 50	6.1	4.82	36.5

Hardware Setup

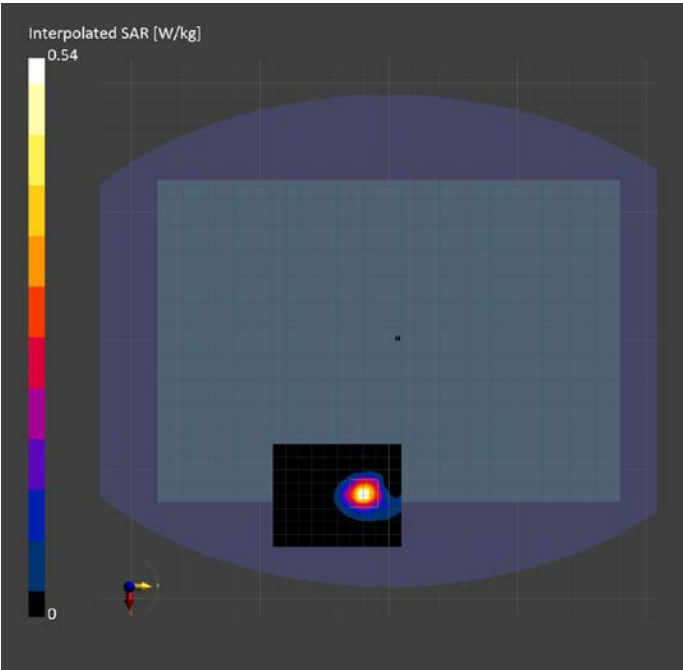
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260310,2026-03-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-10	2026-03-10
psSAR1g [W/kg]	0.360	0.401
psSAR10g [W/kg]	0.118	0.125
Power Drift [dB]		0.17
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		63.2
Dist 3dB Peak [mm]		8.0



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Exposure Conditions

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Flat, Head Simulating Liquid	Bottom, 0.00	WLAN 5GHz	WLAN, 10554-AAE	5250.000, 50	6.1	4.82	36.5

Hardware Setup

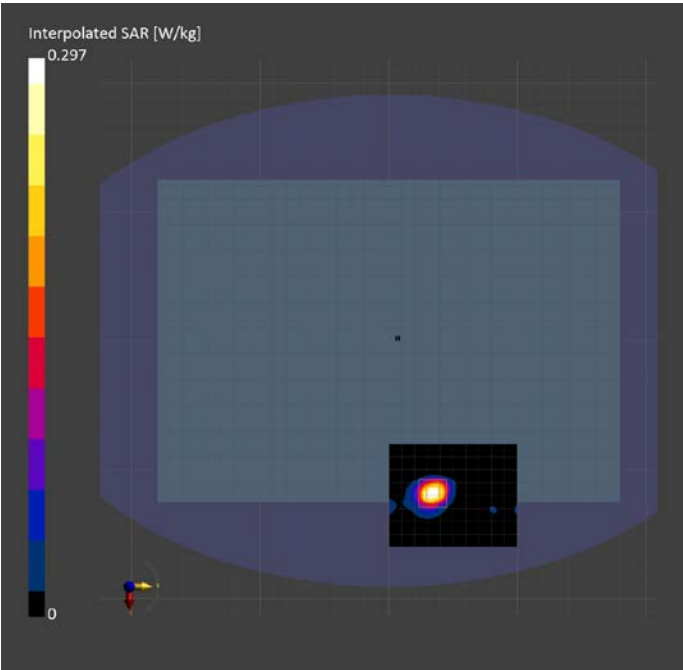
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260310,2026-03-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-10	2026-03-10
psSAR1g [W/kg]	0.214	0.231
psSAR10g [W/kg]	0.070	0.068
Power Drift [dB]		0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		62.6
Dist 3dB Peak [mm]		7.6



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Exposure Conditions

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Flat, Head Simulating Liquid	Bottom, 0.00	WLAN 5GHz	WLAN, 10554-AAE	5570.000, 114	5.54	5.20	36.1

Hardware Setup

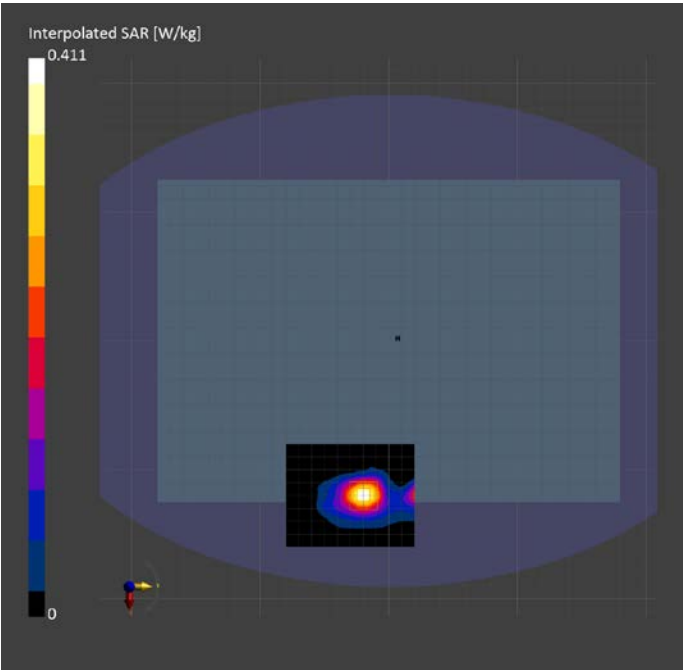
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260310,2026-03-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

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Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-10	2026-03-10
psSAR1g [W/kg]	0.291	0.308
psSAR10g [W/kg]	0.106	0.108
Power Drift [dB]		0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		59.0
Dist 3dB Peak [mm]		10.2



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Flat, Head Simulating Liquid	Bottom, 0.00	WLAN 5GHz	WLAN, 10554-AAE	5570.000, 114	5.54	5.20	36.1

Hardware Setup

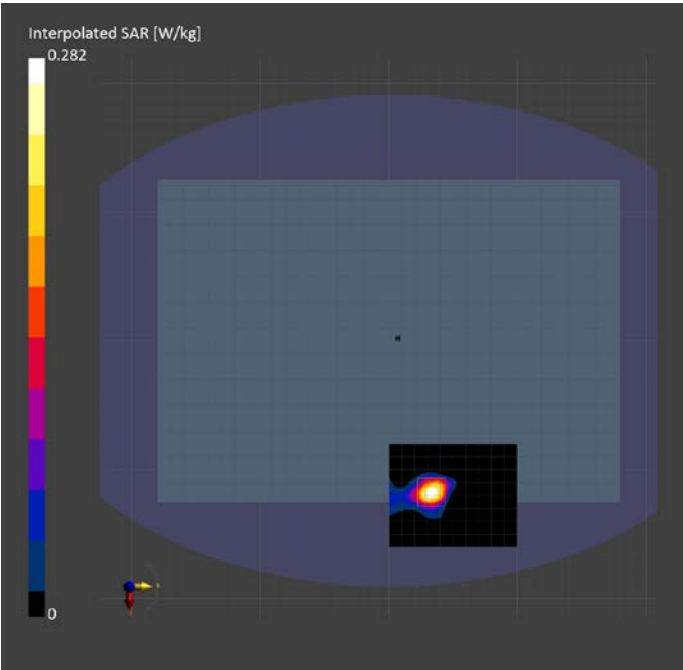
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Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-10	2026-03-10
psSAR1g [W/kg]	0.206	0.225
psSAR10g [W/kg]	0.067	0.069
Power Drift [dB]		0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		59.3
Dist 3dB Peak [mm]		8.7



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Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	WLAN 5GHz	WLAN, 10544-AAD	5775.000, 155	5.42	5.40	35.9

Hardware Setup

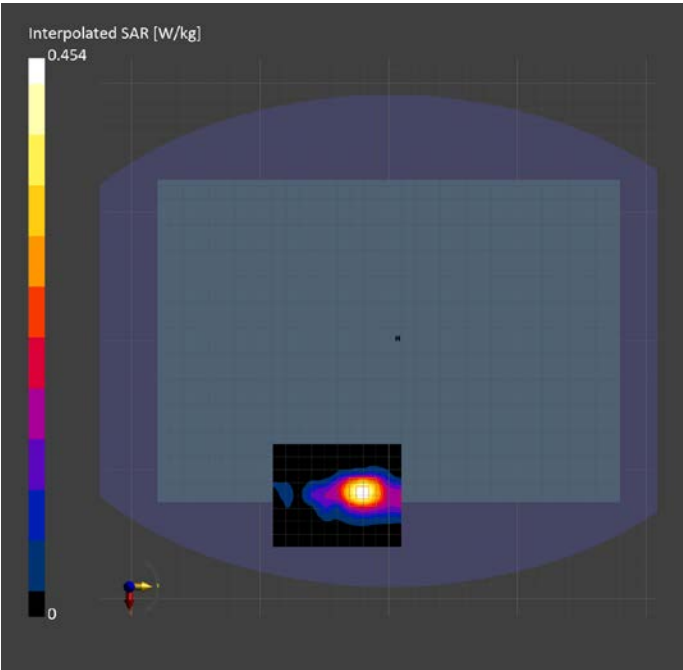
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260310,2026-03-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-10	2026-03-10
psSAR1g [W/kg]	0.342	0.358
psSAR10g [W/kg]	0.129	0.131
Power Drift [dB]		-0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		56.2
Dist 3dB Peak [mm]		10.4



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	WLAN 5GHz	WLAN, 10544-AAD	5775.000, 155	5.42	5.40	35.9

Hardware Setup

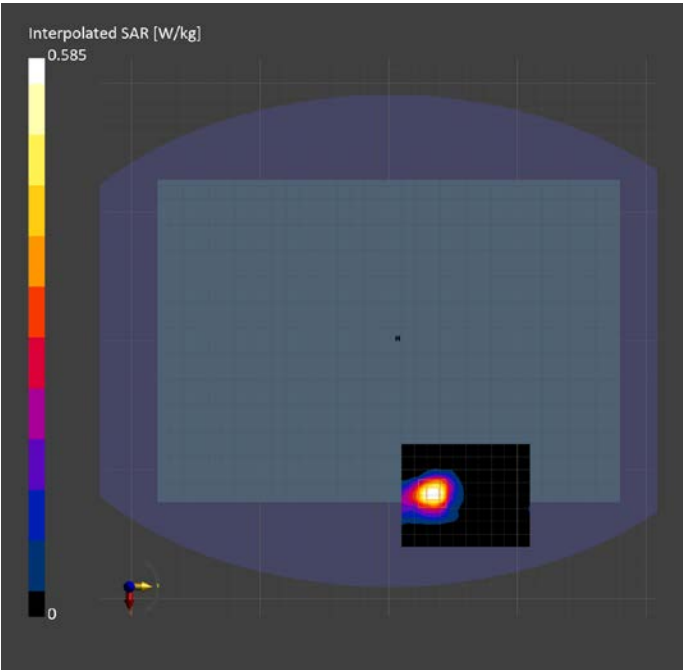
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260310,2026-03-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-10	2026-03-10
psSAR1g [W/kg]	0.442	0.491
psSAR10g [W/kg]	0.160	0.165
Power Drift [dB]		0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		58.0
Dist 3dB Peak [mm]		9.7



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	U-NII-4	WLAN, 10554-AAE	5815.000, 163	5.42	5.48	35.9

Hardware Setup

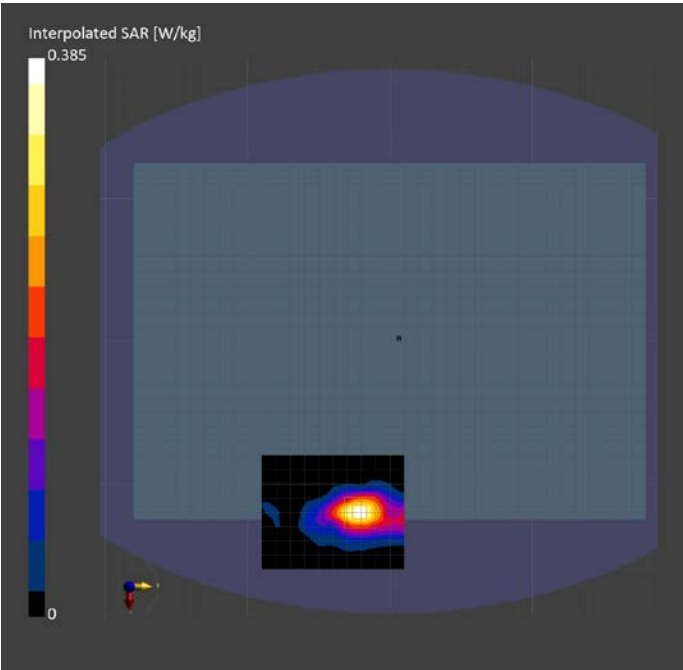
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260310,2026-03-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-10	2026-03-10
psSAR1g [W/kg]	0.281	0.288
psSAR10g [W/kg]	0.105	0.105
Power Drift [dB]		0.18
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		57.4
Dist 3dB Peak [mm]		9.6



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	U-NII-4	WLAN, 10554-AAE	5815.000, 163	5.42	5.48	35.9

Hardware Setup

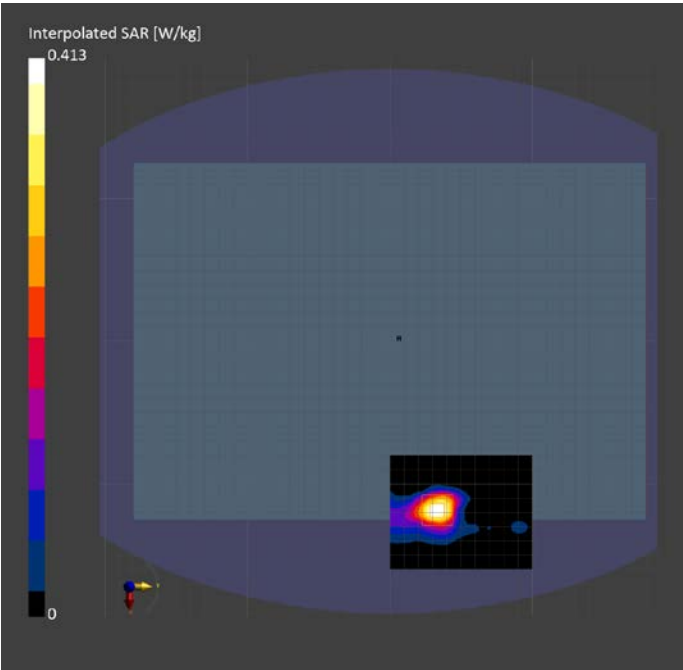
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260310,2026-03-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-10	2026-03-10
psSAR1g [W/kg]	0.310	0.333
psSAR10g [W/kg]	0.112	0.110
Power Drift [dB]		0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		60.3
Dist 3dB Peak [mm]		9.4



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	WLAN 5GHz	WLAN, 10554-AAE	5250.000, 50	6.1	4.77	36.7

Hardware Setup

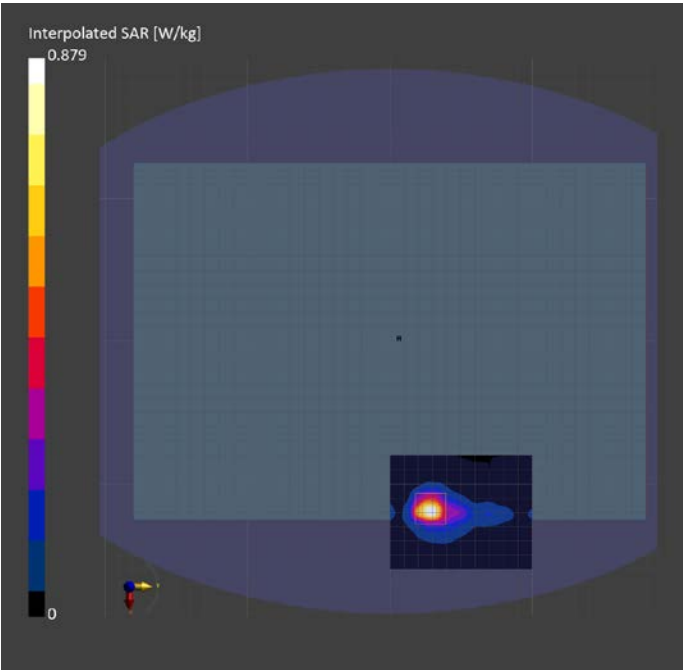
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260311,2026-03-11	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.591	0.717
psSAR10g [W/kg]	0.188	0.194
Power Drift [dB]		0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		63.3
Dist 3dB Peak [mm]		6.4



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	WLAN 5GHz	WLAN, 10554-AAE	5250.000, 50	6.1	4.82	36.5

Hardware Setup

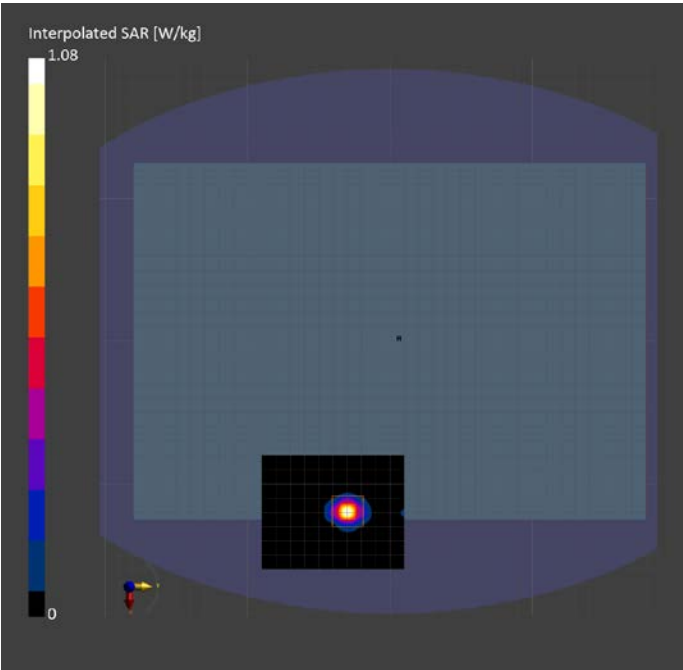
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260310,2026-03-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-10	2026-03-10
psSAR1g [W/kg]	0.643	0.737
psSAR10g [W/kg]	0.167	0.192
Power Drift [dB]		0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		65.1
Dist 3dB Peak [mm]		5.9



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	WLAN 5GHz	WLAN, 10554-AAE	5570.000, 114	5.54	5.15	36.2

Hardware Setup

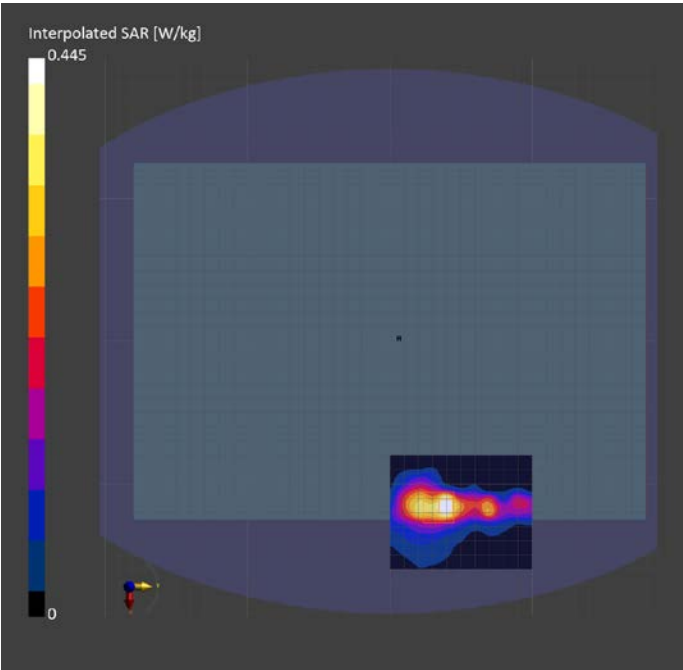
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260311,2026-03-11	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.333	0.383
psSAR10g [W/kg]	0.124	0.121
Power Drift [dB]		0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		60.0
Dist 3dB Peak [mm]		7.2



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	WLAN 5GHz	WLAN, 10554-AAE	5570.000, 114	5.54	5.20	36.1

Hardware Setup

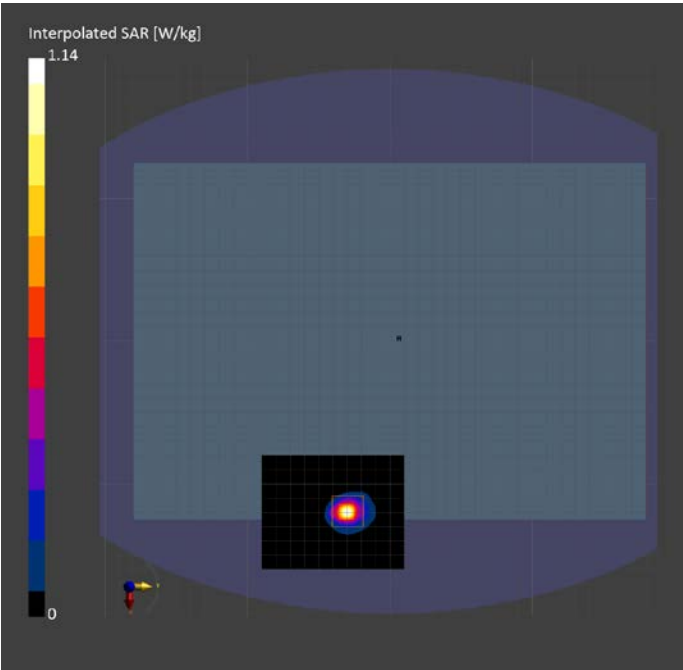
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260310,2026-03-1	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-10	2026-03-10
psSAR1g [W/kg]	0.687	0.785
psSAR10g [W/kg]	0.183	0.207
Power Drift [dB]		0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		62.3
Dist 3dB Peak [mm]		6.4



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	WLAN 5GHz	WLAN, 10544-AAD	5775.000, 155	5.42	5.40	35.9

Hardware Setup

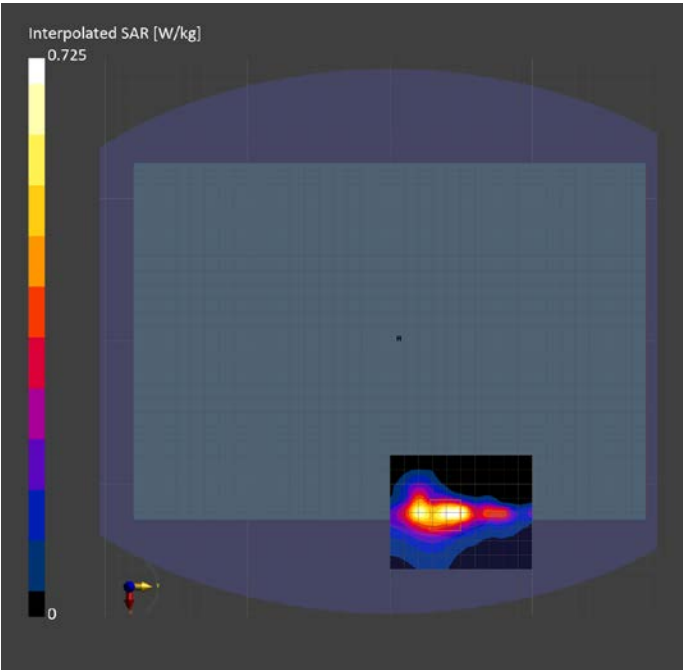
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260310,2026-03-10	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-10	2026-03-10
psSAR1g [W/kg]	0.519	0.477
psSAR10g [W/kg]	0.185	0.165
Power Drift [dB]		-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		57.4
Dist 3dB Peak [mm]		8.6



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	WLAN 5GHz	WLAN, 10544-AAD	5775.000, 155	5.42	5.36	36.0

Hardware Setup

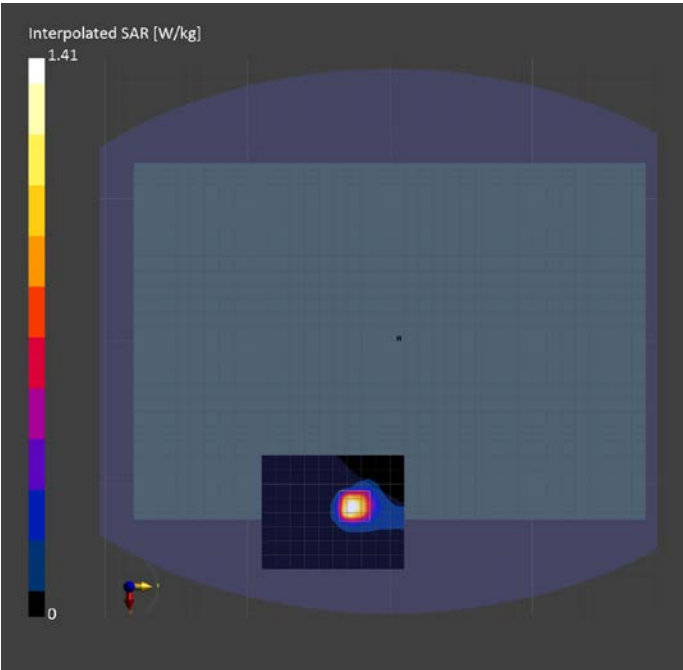
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260311,2026-03-11	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	1.04	1.35
psSAR10g [W/kg]	0.328	0.343
Power Drift [dB]		-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		56.1
Dist 3dB Peak [mm]		6.4



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	U-NII-4	WLAN, 10554-AAE	5815.000, 163	5.42	5.44	36.0

Hardware Setup

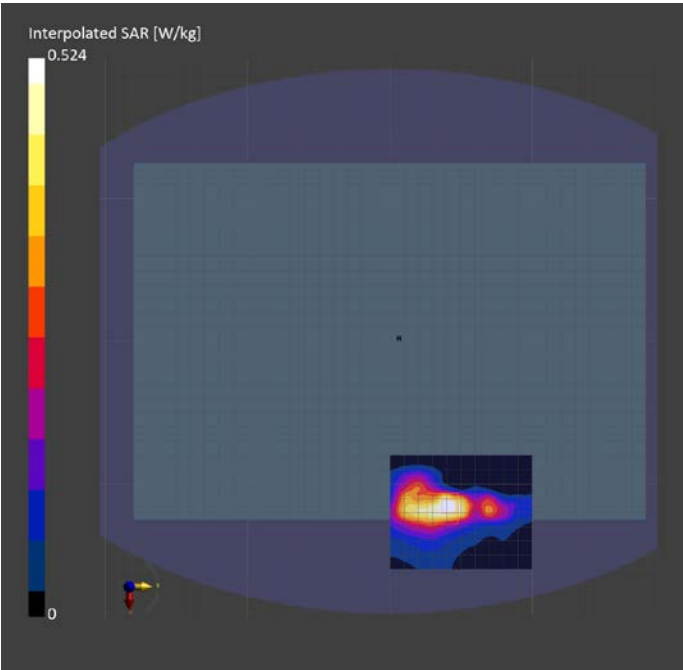
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260311,2026-03-11	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.407	0.454
psSAR10g [W/kg]	0.157	0.150
Power Drift [dB]		-0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		58.7
Dist 3dB Peak [mm]		7.2



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	U-NII-4	WLAN, 10554-AAE	5815.000, 163	5.42	5.44	36.0

Hardware Setup

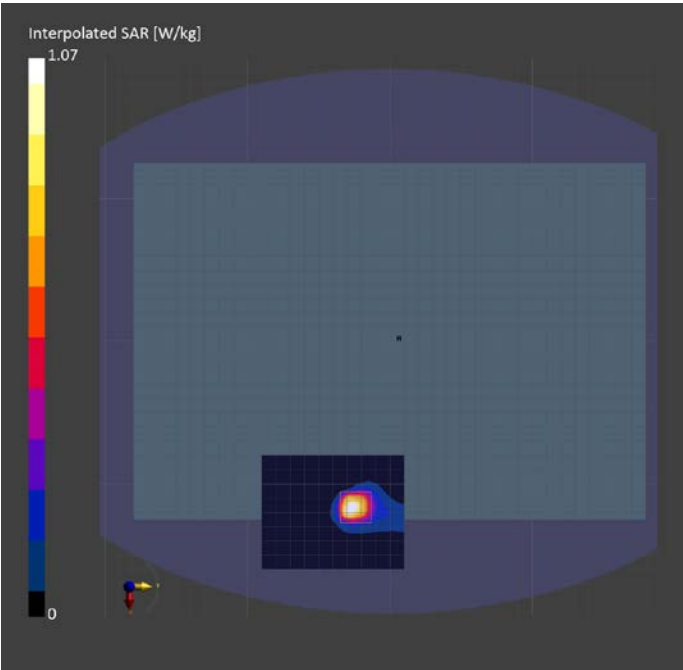
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2273	h5G-260311,2026-03-11	EX3DV4 - SN7678, 2025-08-21	DAE4 Sn1764, 2025-04-22

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	70.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.789	1.10
psSAR10g [W/kg]	0.247	0.277
Power Drift [dB]		0.16
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		57.5
Dist 3dB Peak [mm]		6.4



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	U-NII-5	WLAN, 10755-AAC	6345.000, 79	5.63	6.03	35.5

Hardware Setup

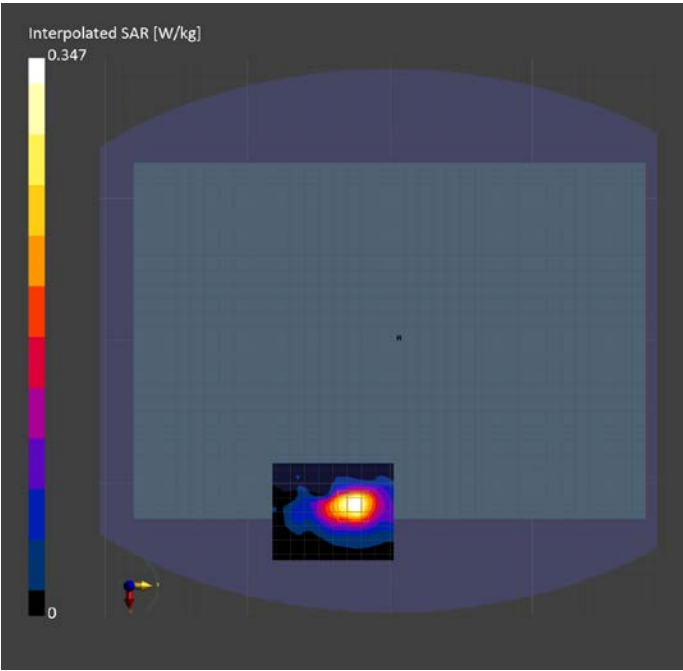
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260312,2026-03-12	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-12	2026-03-12
psSAR1g [W/kg]	0.269	0.298
psSAR10g [W/kg]	0.10	0.109
psAPD (1.0cm2, sq) [W/m2]		2.98
psAPD (4.0cm2, sq) [W/m2]		2.46
Power Drift [dB]		-0.17
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		49.3
Dist 3dB Peak [mm]		11.1



Test Laboratory: BTL

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	U-NII-5	WLAN, 10755-AAC	6345.000, 79	5.63	6.03	35.5

Hardware Setup

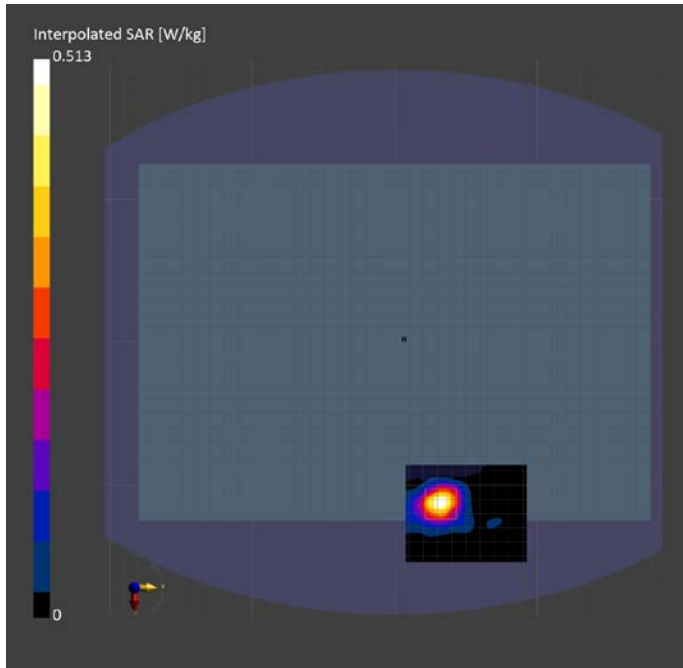
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260312, 2026-03-12	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-12	2026-03-12
psSAR1g [W/kg]	0.379	0.420
psSAR10g [W/kg]	0.129	0.139
psAPD (1.0cm2, sq) [W/m2]		4.20
psAPD (4.0cm2, sq) [W/m2]		3.19
Power Drift [dB]		0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		50.0
Dist 3dB Peak [mm]		8.9



Test Laboratory: BTL

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	U-NII-6	WLAN, 10755-AAC	6505.000, 111	5.63	5.97	34.2

Hardware Setup

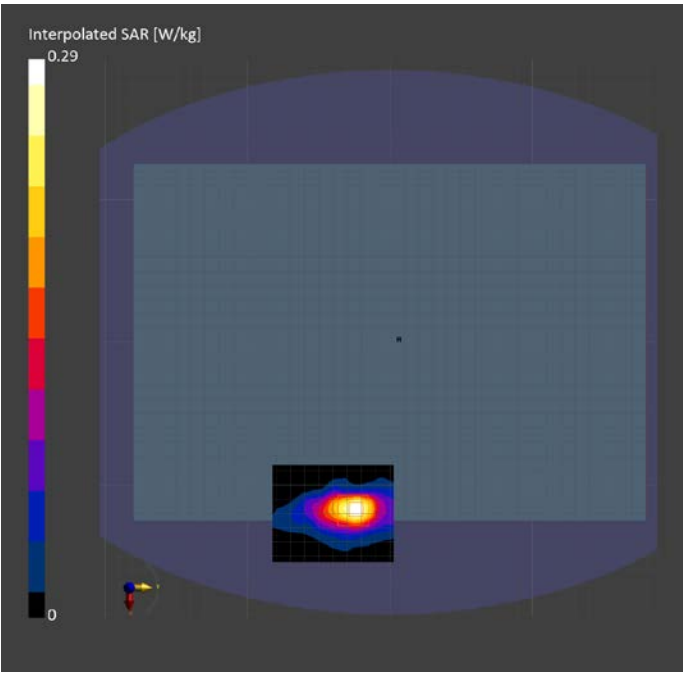
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260311, 2026-03-11	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.230	0.254
psSAR10g [W/kg]	0.084	0.092
psAPD (1.0cm2, sq) [W/m2]		2.54
psAPD (4.0cm2, sq) [W/m2]		2.09
Power Drift [dB]		-0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		49.0
Dist 3dB Peak [mm]		9.9



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	U-NII-6	WLAN, 10755-AAC	6505.000, 111	5.63	5.97	34.2

Hardware Setup

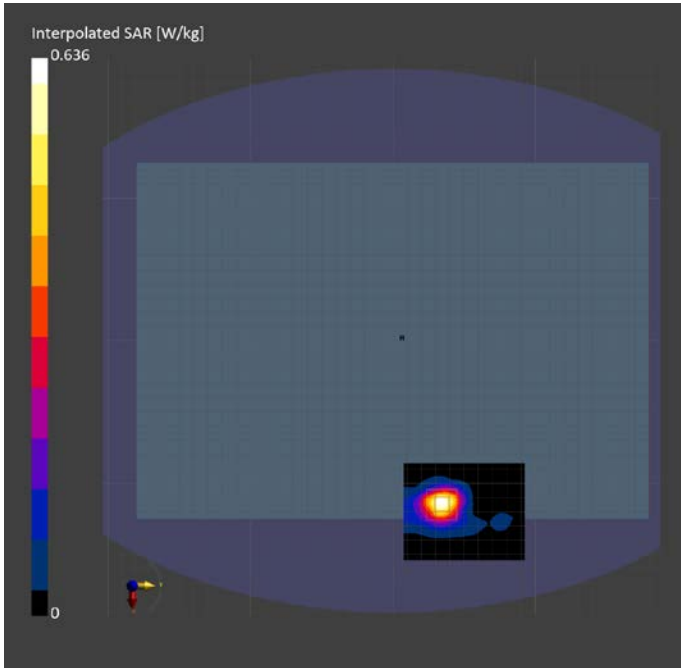
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260311,2026-03-11	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.483	0.531
psSAR10g [W/kg]	0.163	0.179
psAPD (1.0cm2, sq) [W/m2]		5.31
psAPD (4.0cm2, sq) [W/m2]		4.11
Power Drift [dB]		0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		48.8
Dist 3dB Peak [mm]		9.1



Test Laboratory: BTL

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	U-NII-7	WLAN, 10755-AAC	6825.000, 175	5.63	6.35	33.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260311, 2026-03-11	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

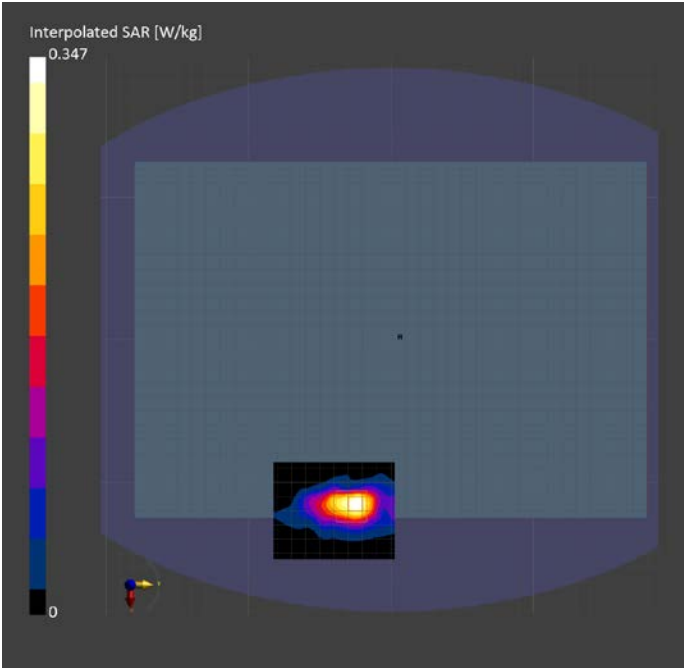
	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.282	0.310
psSAR10g [W/kg]	0.102	0.106
psAPD (1.0cm2, sq) [W/m2]		3.10
psAPD (4.0cm2, sq) [W/m2]		2.43
Power Drift [dB]		0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only

M2/M1 [%]46.4

Dist 3dB Peak [mm]9.1



Test Laboratory: BTL

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	U-NII-7	WLAN, 10755-AAC	6825.000, 175	5.63	6.35	33.8

Hardware Setup

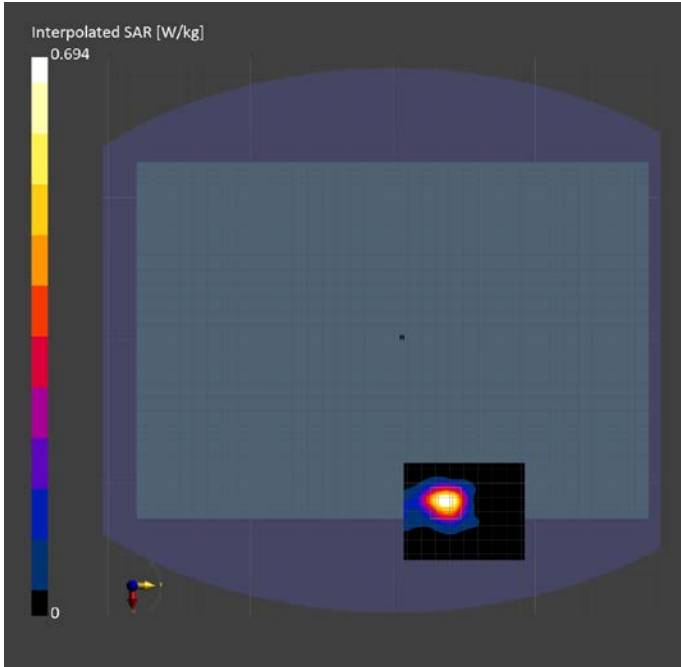
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260311,2026-03-11	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.553	0.607
psSAR10g [W/kg]	0.182	0.193
psAPD (1.0cm2, sq) [W/m2]		6.07
psAPD (4.0cm2, sq) [W/m2]		4.48
Power Drift [dB]		-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		46.6
Dist 3dB Peak [mm]		7.7



Test Laboratory: BTL

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	U-NII-8	WLAN, 10755-AAC	6985.000, 207	5.63	6.50	33.7

Hardware Setup

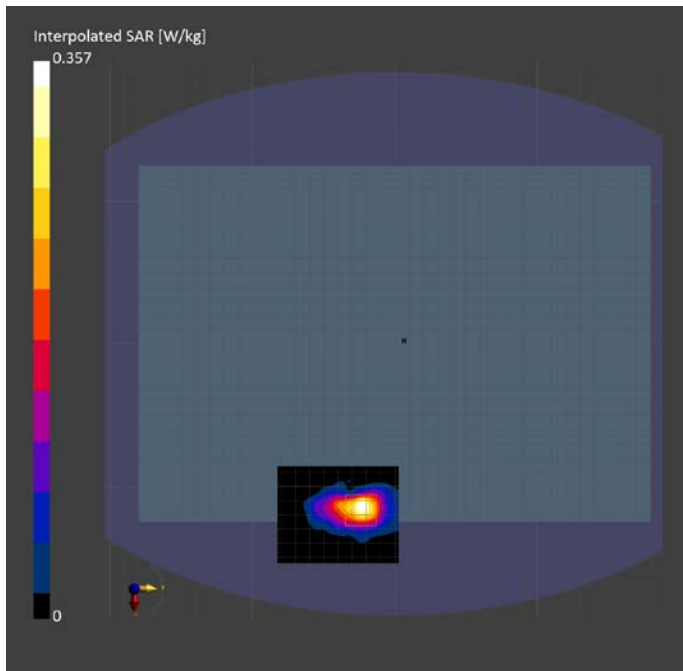
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260311, 2026-03-11	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.286	0.306
psSAR10g [W/kg]	0.098	0.103
psAPD (1.0cm2, sq) [W/m2]		3.06
psAPD (4.0cm2, sq) [W/m2]		2.36
Power Drift [dB]		-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		44.1
Dist 3dB Peak [mm]		9.7



Test Laboratory: BTL

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Bottom, 0.00	U-NII-8	WLAN, 10755-AAC	6985.000, 207	5.63	6.50	33.7

Hardware Setup

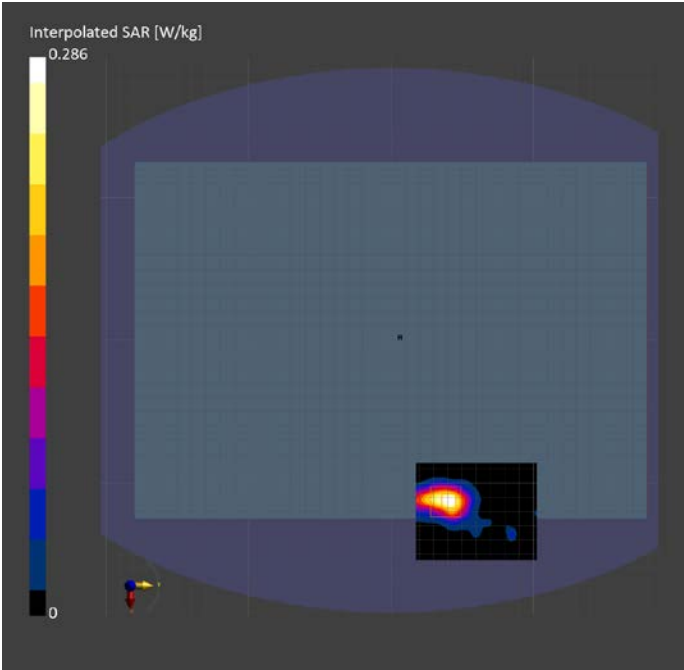
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260311,2026-03-11	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.228	0.251
psSAR10g [W/kg]	0.077	0.082
psAPD (1.0cm2, sq) [W/m2]		2.51
psAPD (4.0cm2, sq) [W/m2]		1.89
Power Drift [dB]		-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		45.4
Dist 3dB Peak [mm]		6.2



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	U-NII-5	WLAN, 10755-AAC	6345.000, 79	5.63	5.79	34.5

Hardware Setup

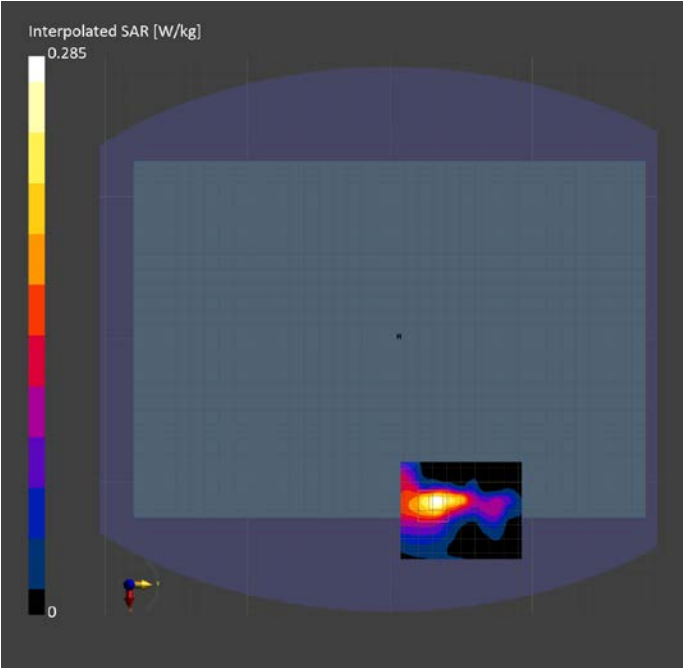
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260311,2026-03-11	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.210	0.237
psSAR10g [W/kg]	0.075	0.081
psAPD (1.0cm2, sq) [W/m2]		2.37
psAPD (4.0cm2, sq) [W/m2]		1.84
Power Drift [dB]		0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		49.3
Dist 3dB Peak [mm]		8.3



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	U-NII-5	WLAN, 10755-AAC	6185.000, 47	5.63	5.86	35.7

Hardware Setup

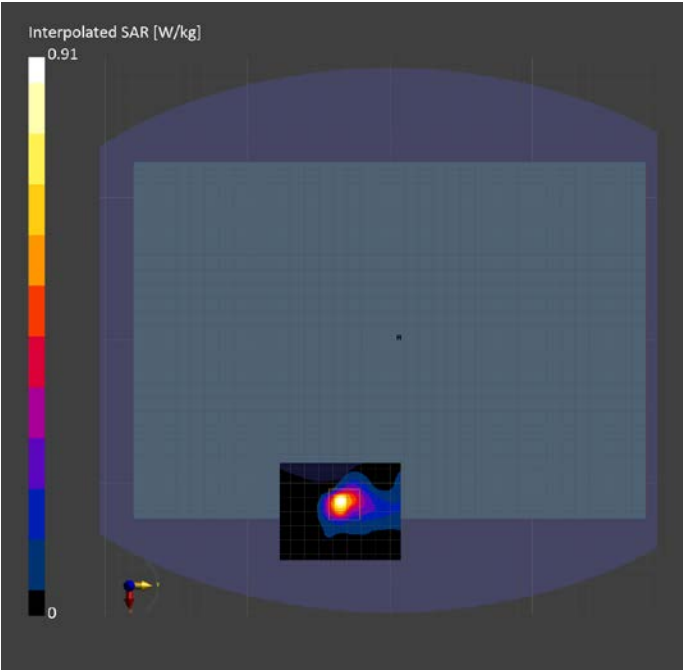
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260312,2026-03-12	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-12	2026-03-12
psSAR1g [W/kg]	0.603	0.699
psSAR10g [W/kg]	0.180	0.196
psAPD (1.0cm2, sq) [W/m2]		6.99
psAPD (4.0cm2, sq) [W/m2]		4.58
Power Drift [dB]		-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		52.2
Dist 3dB Peak [mm]		6.5



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
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Flat, Head Simulating Liquid	Top of keyboard, 0.00	U-NII-6	WLAN, 10755-AAC	6505.000, 111	5.63	5.97	34.2
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Hardware Setup

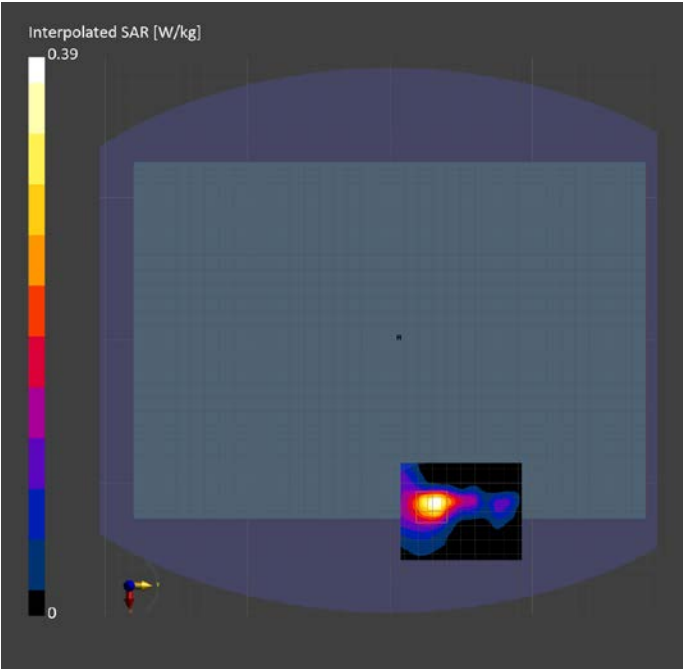
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260311,2026-03-11	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.292	0.326
psSAR10g [W/kg]	0.100	0.107
psAPD (1.0cm2, sq) [W/m2]		3.26
psAPD (4.0cm2, sq) [W/m2]		2.46
Power Drift [dB]		-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		50.0
Dist 3dB Peak [mm]		8.2



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	U-NII-6	WLAN, 10755-AAC	6505.000, 111	5.63	6.20	35.3

Hardware Setup

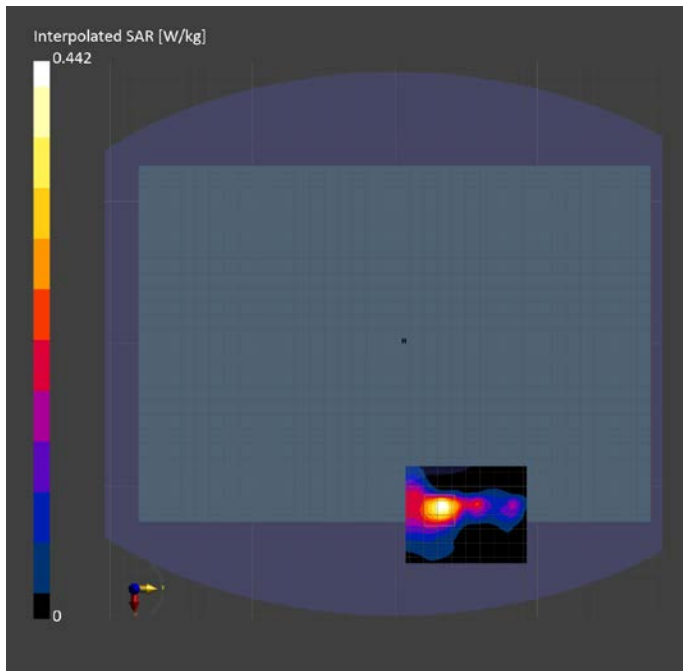
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260312, 2026-03-12	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-12	2026-03-12
psSAR1g [W/kg]	0.328	0.376
psSAR10g [W/kg]	0.111	0.119
psAPD (1.0cm2, sq) [W/m2]		3.76
psAPD (4.0cm2, sq) [W/m2]		2.74
Power Drift [dB]		0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		48.7
Dist 3dB Peak [mm]		6.8



Test Laboratory: BTL

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	U-NII-7	WLAN, 10755-AAC	6825.000, 175	5.63	6.35	33.8

Hardware Setup

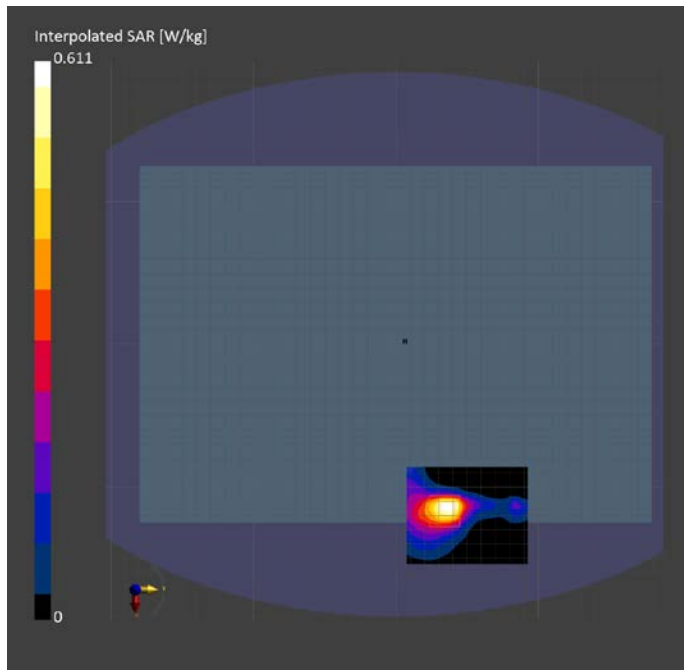
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260311, 2026-03-11	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.497	0.534
psSAR10g [W/kg]	0.177	0.183
psAPD (1.0cm2, sq) [W/m2]		5.34
psAPD (4.0cm2, sq) [W/m2]		4.20
Power Drift [dB]		0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		47.9
Dist 3dB Peak [mm]		8.9



Test Laboratory: BTL

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	U-NII-7	WLAN, 10755-AAC	6825.000, 175	5.63	6.54	34.9

Hardware Setup

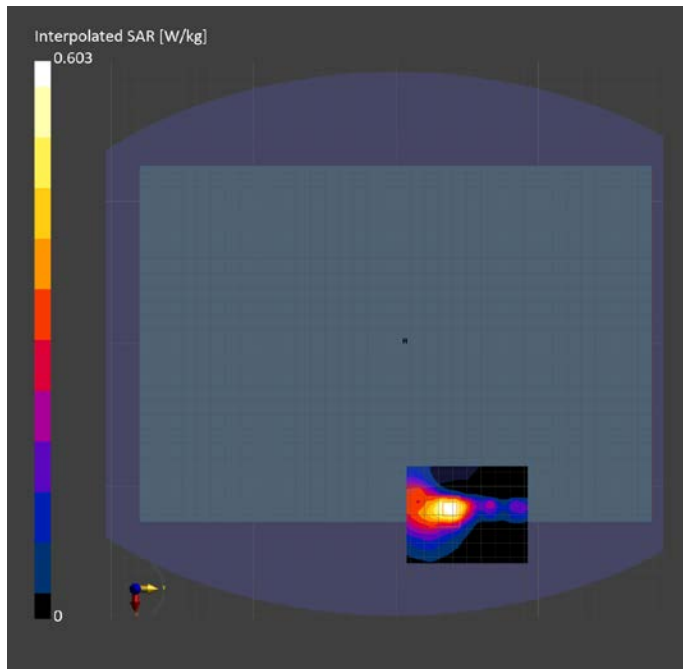
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260312, 2026-03-12	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-12	2026-03-12
psSAR1g [W/kg]	0.495	0.544
psSAR10g [W/kg]	0.177	0.183
psAPD (1.0cm2, sq) [W/m2]		5.44
psAPD (4.0cm2, sq) [W/m2]		4.21
Power Drift [dB]		0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		47.0
Dist 3dB Peak [mm]		8.2



Test Laboratory: BTL

Device under Test Properties

Project No.: 2601T049

Page 39 of 42

Report Version:
R00

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	U-NII-8	WLAN, 10755-AAC	6985.000, 207	5.63	6.50	33.7

Hardware Setup

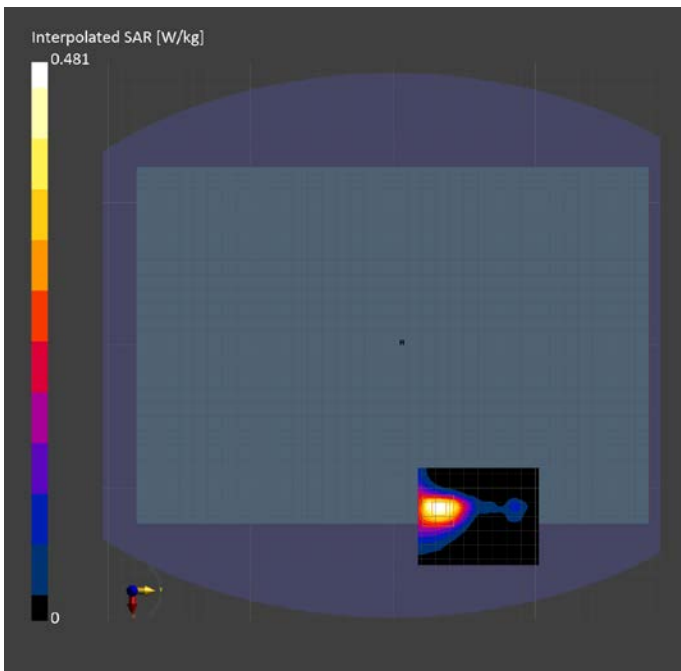
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260311 ,2026-03-11	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-11	2026-03-11
psSAR1g [W/kg]	0.396	0.421
psSAR10g [W/kg]	0.143	0.146
psAPD (1.0cm2, sq) [W/m2]		4.21
psAPD (4.0cm2, sq) [W/m2]		3.33
Power Drift [dB]		0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		46.1
Dist 3dB Peak [mm]		8.9



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	Top of keyboard, 0.00	U-NII-8	WLAN, 10755-AAC	6985.000, 207	5.63	6.70	34.7

Hardware Setup

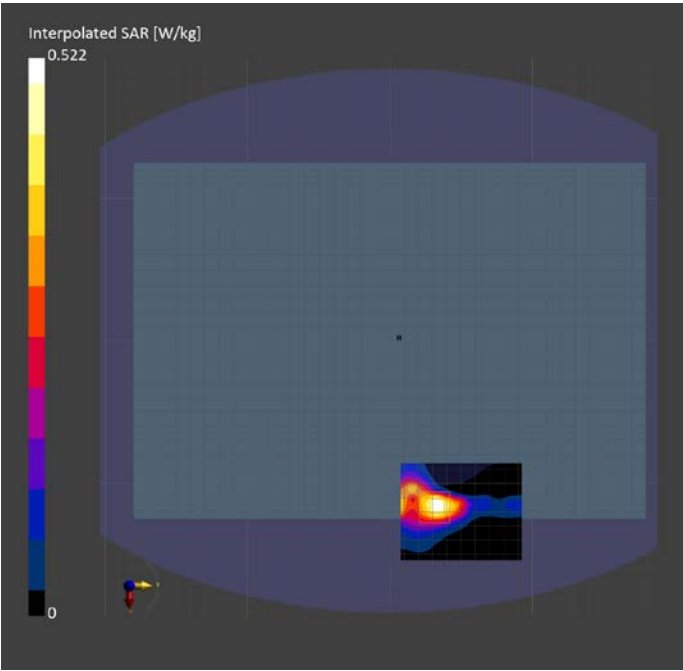
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V5.0 (20deg probe tilt) - 1240	h6G-260312,2026-03-12	EX3DV4 - SN7369, 2025-05-21	DAE4 Sn1486, 2025-06-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	68.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-03-12	2026-03-12
psSAR1g [W/kg]	0.433	0.479
psSAR10g [W/kg]	0.152	0.158
psAPD (1.0cm2, sq) [W/m2]		4.79
psAPD (4.0cm2, sq) [W/m2]		3.60
Power Drift [dB]		-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		46.1
Dist 3dB Peak [mm]		8.2



Test Laboratory: BTL
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
, Device	360.0 x 250.0 x 19.0		Laptop

Exposure Conditions

Phantom Section	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor
5G Air	Bottom, 2.00	U-NII-7	WLAN, 10755-AAC	6825.0, 175	1.0

Hardware Setup

Phantom	Medium	Probe, Calibration Date	DAE, Calibration Date
mmWave- 1085	---Air	EUmmWV4 - SN9586_F1-55GHz, 2025-06-17	DAE4 Sn1486, 2025-06-24

Scan Setup

	5G Scan
Grid Extents [mm]	100.0 x 100.0
Grid Steps [lambda]	0.125 x 0.125
Sensor Surface [mm]	2.0
MAIA	Y

Measurement Results

	5G Scan
Date	2026-03-17
Avg. Area [cm ²]	4.00
psPDn+ [W/m ²]	3.38
psPDtot+ [W/m ²]	5.01
psPDmod+ [W/m ²]	5.99
E _{max} [V/m]	59.0
Power Drift [dB]	0.56

